to Table II, Group C end-point electrical parametersgz.     C   Updated drawing paragraphssld   12-05-15   Charles F. Si     C     Updated drawing paragraphssld   12-05-15   Charles F. Si     SHEET     REV   Image: state sta									R	EVISI	ONS										
B   Figure 2, case outlines N and T, correct terminal number 2. Add note   08-09-02   Charles F. Si     C   Updated drawing paragraphssld   12-05-15   Charles F. Si     C   Updated drawing paragraphssld   12-05-15   Charles F. Si     SHEET   Image: correct terminal number 2. Add note   08-09-02   Charles F. Si     SHEET   Image: correct terminal number 2. Add note   12-05-15   Charles F. Si     SHEET   Image: correct terminal number 2. Add note   Image: correct terminal number 2. Add note   Image: correct terminal number 2. Add note     SHEET   Image: correct terminal number 2. Add note     SHEET   Image: correct terminal number 2. Add not number 2. Add n	LTR	DESCRIPTION									DA	TE (YI	R-MO-	-DA)		APPR		)			
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REV Image: Strandard Barger	В	Figu	re 2, case outlines N and T, correct terminal number 2. Add note							09-09-02		Charles F. Saffle									
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REV STATUS   REV   C <t< td=""><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td><td></td></t<>																					
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PMIC N/A   PREPARED BY Gary Zahn   DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990 http://www.landandmaritime.dla.mil/     STANDARD MICROCIRCUIT DRAWING   CHECKED BY Michael C. Jones   DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990 http://www.landandmaritime.dla.mil/     THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS   APPROVED BY Raymond Monnin   MICROCIRCUIT, LINEAR, VOLTAGE REGULATOR, 15 VOLT, NEGATIVE, FIXEI		6														-					
Gary Zahn   DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990     MICROCIRCUIT DRAWING   CHECKED BY Michael C. Jones   http://www.landandmaritime.dla.mil/     THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS   APPROVED BY Raymond Monnin   MICROCIRCUIT, LINEAR, VOLTAGE REGULATOR, 15 VOLT, NEGATIVE, FIXEI								1	2	3	4	5	6	1	8	9	10	11			
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AMSC N/A REVISION LEVEL SIZE CAGE CODE C A <b>67268 5962-98641</b>	AMS	SC N/A			REV	ISION					/	٩						5962·	-9864	1	
DSCC FORM 2233											SHE	ET		1	OF	11					

# 1. SCOPE

1.1 <u>Scope</u>. This drawing documents five product assurance classes as defined in paragraph 1.2.3 and MIL-PRF-38534. A choice of case outlines and lead finishes which are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.

1.2 <u>PIN</u>. The PIN shall be as shown in the following example:

5962	-	98641	01	<u>H</u>	<u>T</u>	<u>A</u>
1/2	1/2		1/2	1/2	1/2	1/2
1/2	1/2		1/2	1/2	1/2	1/2
1/2	1/2		1/2	1/2	1/2	1/2
Federal	RHA		Device	Device	Case	Lead
stock class	designator		type	class	outline	finish
designator	(see 1.2.1)		(see 1.2.2)	designator	(see 1.2.4)	(see 1.2.5)
١		/		(see 1.2.3)		
	17					

Drawing number

1.2.1 <u>Radiation hardness assurance (RHA) designator</u>. RHA marked devices shall meet the MIL-PRF-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.

1.2.2 <u>Device type(s)</u>. The device type(s) identify the circuit function as follows:

Device type	<u>Generic number</u> <u>1</u> /	Circuit function
01	SDP7915A	Negative voltage regulator, 15 volt, fixed

1.2.3 <u>Device class designator</u>. This device class designator shall be a single letter identifying the product assurance level. All levels are defined by the requirements of MIL-PRF-38534 and require QML Certification as well as qualification (Class H, K, and E) or QML Listing (Class G and D). The product assurance levels are as follows:

Device class	Device performance documentation						
К	Highest reliability class available. This level is intended for use in space applications.						
Н	Standard military quality class level. This level is intended for use in applications where non-space high reliability devices are required.						
G	Reduced testing version of the standard military quality class. This level uses the Class H screening and In-Process Inspections with a possible limited temperature range, manufacturer specified incoming flow, and the manufacturer guarantees (but may not test) periodic and conformance inspections (Group A, B, C and D).						
E	E Designates devices which are based upon one of the other classes (K, H, or G) with exception(s) taken to the requirements of that class. These exception(s) must be specified in the device acquisition document; therefore the acquisition document should be reviewed to ensure that the exception(s) taken will not adversely affect system performance.						
D			Quality level is defined by duct may have a limited ten				
he SDP7915A is similar to the 7915A listed on Standard Microcircuit Drawing 5962-88748.							
STANDARD MICROCIRCUIT DRAW	/ING	SIZE A		5962-98641			
DLA LAND AND MARITIN COLUMBUS, OHIO 43218-3			REVISION LEVEL C	SHEET 2			

<u>1/</u> T

1.2.4 Case outline(s).	The case outline(s) are as designa	ted in MIL-ST	D-1835	and as follows:	
Outline letter	Descriptive designator	<u>Terminals</u>		Package style	
Ν	See figure 1	3		Z-tab with nonisolated	-
т	See figure 1	3		(TO-257Z), with glass Flange mount with nonisc	lated tab,
U	See figure 1	3		(TO-257), with glass Flange mount with isola	ted tab,
Z	See figure 1	3		(TO-257), with glass Z-tab with isolated t (TO-257Z), with glass	tab,
1.2.5 Lead finish. The	lead finish shall be as specified in	MIL-PRF-385	534.		
1.3 Absolute maximum	<u>n ratings</u> . <u>1</u> /				
Transient Storage temperature Lead temperature (so Junction temperature Power dissipation (Pr $T_C = +25^{\circ}C$ $T_A = +25^{\circ}C$ Thermal resistance, j Cases N and T Cases U and Z Thermal resistance, j 1.4 <u>Recommended operature</u> Input voltage range Ambient operating ter 2. APPLICABLE DOCU 2.1 <u>Government specifi</u> of this drawing to the extersion or contract. DEPARTMENT OF D MIL-PRF-38534 -	unction-to-case (q <sub>JC</sub> ): unction-to-ambient (q <sub>JA</sub> ) erating conditions. mperature range (T <sub>A</sub> ) JMENTS ication, standards, and handbooks int specified herein. Unless otherw DEFENSE SPECIFICATIONS Hybrid Microcircuits, General Spe	. The followir ise specified, cification for.	+300°( +150°( 15 W 3.0 W 3.5°C/ 4.2°C/ 42°C/V -17.5 \ -55°C	dc <u>2/</u> to +150°C C <u>3/</u> W W V / dc to -30 V dc to +125°C fication, standards, and har les of these documents are	those cited in the
the maximum levels n <u>2</u> / The -50 volt input ratin damage. Since the re- input voltages under r <u>3</u> / The device is protected	nay degrade performance and affecting refers to the ability of the regulation gulator's maximum current capability of the regulation.	ct reliability. or to withstar ty is reduced	nd high li , the out	ine or transient condition wi put may fall out of regulatio	ithout n at high
S	[ANDARD	SIZ			5000 00044
MICROCI	RCUIT DRAWING	A	<b>`</b>		5962-98641
	<b>ID AND MARITIME</b> S, OHIO 43218-3990			REVISION LEVEL C	SHEET 3

## DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits. MIL-STD-1835 - Interface Standard for Electronic Component Case Outlines.

## DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings. MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at https://assist.daps.dla.mil/quicksearch/ or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

# 3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item performance requirements for device classes D, E, G, H, and K shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 shall include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for the applicable device class. The manufacturer may eliminate, modify or optimize the tests and inspections herein, however the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class. In addition, the modification in the QM plan shall not affect the form, fit, or function of the device for the applicable device class.

3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.

3.2.1 <u>Case outlines</u>. The case outlines shall be in accordance with 1.2.4 herein and figure 1.

3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.

3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.6 <u>Data</u>. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DLA Land and Maritime -VA) upon request.

3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DLA Land and Maritime -VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.

3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

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Test	TABLE I. <u>Electrical performance characteristics</u> .     Test   Symbol   Conditions 1/   Group A   Device   Limits   Unit							
	Symbol	Conditions $\frac{1}{25^{\circ}C}$	Group A subgroups	Device type	Lin	nits	Unit	
		$-55^{\circ}C \le T_A \le +125^{\circ}C$ unless otherwise specified	Jubyicape	.960	Min	Max		
Output voltage	V <sub>OUT</sub>	T <sub>A</sub> = +25°C	1	01	-14.85	-15.15	V	
		V <sub>IN</sub> = -17.5 V to -30 V <u>2</u> /	1, 2, 3		-14.55	-15.45		
Line regulation <u>3</u> / <u>4</u> /	V <sub>RLINE</sub>	V <sub>IN</sub> = -17.5 V to -30 V	1	01		20	mV	
			2, 3			50		
		$V_{IN} = -20 V \text{ to } -26 V$	1	01		15	mV	
			2, 3			25	<b></b>	
Load regulation <u>3</u> /	V <sub>RLOAD</sub>	$V_{IN} = -20 V,$	1	01		35	mV	
		I <sub>O</sub> = 5.0 mA to 1.5 A	2, 3	ļ		75	<u> </u>	
		$V_{IN} = -20 V,$	1	01		21	mV	
		I <sub>O</sub> = 250 mA to 750 mA	2, 3			45		
Standby current drain	I <sub>SCD</sub>		1	01		6.0	mA	
			2, 3			6.5		
Standby current drain change with line	D I <sub>SCD</sub> (line)	V <sub>IN</sub> = -17.5 V to -30 V	1, 2, 3	01		0.8	mA	
Standby current drain change with load	D I <sub>SCD</sub> (load)	I <sub>O</sub> = 5.0 mA to 1.0 A	1, 2, 3	01		0.5	mA	
Dropout voltage	V <sub>DO</sub>	$\Delta V_{OUT} = 100 \text{ mV},$ I <sub>O</sub> = 1.0 A	1, 2, 3	01		2.5	V	
Peak output current	I <sub>O(pk)</sub>	T <sub>A</sub> = +25°C	1	01	1.5	3.3	А	
Short circuit current <u>5</u> /	I <sub>OS</sub>	V <sub>IN</sub> = -35 V	1	01		1.2	А	
			2, 3			2.8		
Ripple rejection	DVIN DVout	f = 120 Hz, I <sub>O</sub> = 0.5 A,	4	01	53		dB	
		V <sub>IN</sub> = -18 V to -28 V	5, 6 <u>6</u> /		50			
See footnotes at end of tabl	e.							

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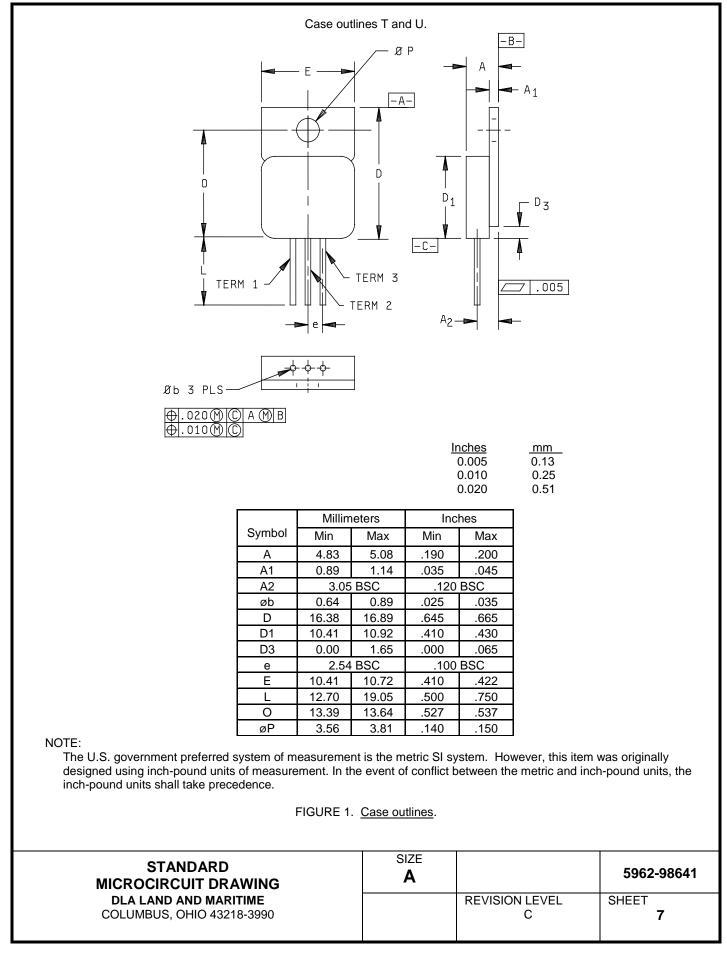
TABLE I. Electrical performance characteristics – Continued.							
Test	Symbol	Conditions <u>1</u> /	Group A	Device	Limits		Unit
		$-55^{\circ}C \le T_A \le +125^{\circ}C$ unless otherwise specified	subgroups	type	Min	Max	
Output noise voltage <u>6</u> /	N <sub>O</sub>	f = 10 Hz to 100 kHz, T <sub>A</sub> = +25°C	7	01		40	μV/V rms
Long term stability <u>6</u> /	DVout Dt	t = 1000 hours, T <sub>A</sub> = +25°C	7	01		150	mV

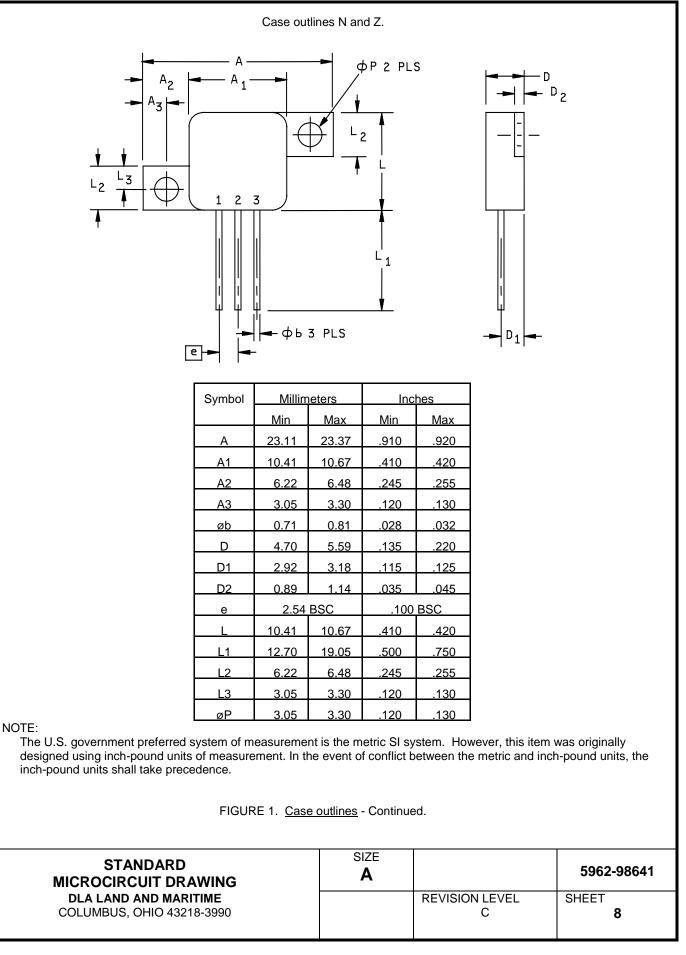
 $\underline{1}/~$  Unless otherwise specified, V  $_{\rm IN}$  = -23 V and I  $_{\rm O}$  = 500 mA.

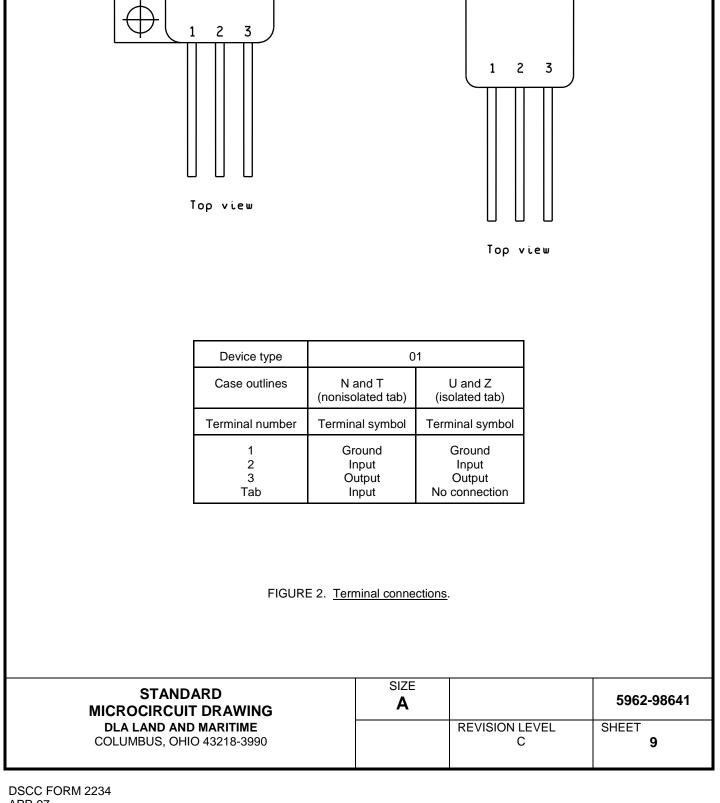
<u>2</u>/  $I_0 = 5 \text{ mA to } 1.0 \text{ A}, \text{ P } \pounds 15 \text{ W}.$ 

- 3/ All measurements except output noise voltage and ripple rejection are made at constant junction temperature and with low duty cycle.
- 4/ Minimum load current for full line regulation is 5.0 mA.
- $\underline{5}/~$  Short circuit protection is only assured up to V  $_{\text{IN}}$  = -35 V.
- 6/ If not tested, shall be guaranteed to the limits specified in table I.

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Case outlines T and U

Case outlines N and Z

# APR 97

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	1
Final electrical parameters	1*, 2, 3, 4
Group A test requirements	1, 2, 3, 4, 5**, 6**, 7**
Group C end-point electrical parameters <u>1</u> /	1, 2, 3
End-point electrical parameters for Radiation Hardness Assurance (RHA) devices	Not applicable

TABLE II. Electrical test requirements.

\* PDA applies to subgroup 1.

- \*\* Subgroups 5, 6, and 7, if not tested shall be guaranteed to the limits specified in table I.
- 1/ As a minimum, for all Group C testing performed after September 2, 2009 manufacturers shall perform subgroups 1, 2, and 3 from the Group A electrical test table (Table C-Xa of MIL-PRF-38534).

# 4. VERIFICATION

4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

4.2 <u>Screening</u>. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
  - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DLA Land and Maritime -VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
  - (2) T<sub>A</sub> as specified in accordance with table I of method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 <u>Conformance and periodic inspections</u>. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.

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- 4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:
  - a. Tests shall be as specified in table II herein.
  - b. Subgroups 8, 9, 10, and 11 shall be omitted.
- 4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.
- 4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:
  - a. End-point electrical parameters shall be as specified in table II herein.
  - b. Steady-state life test, method 1005 of MIL-STD-883.
    - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DLA Land and Maritime -VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
    - (2)  $T_A$  as specified in accordance with table I of method 1005 of MIL-STD-883.
    - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.

4.3.5 Radiation Hardness Assurance (RHA) inspection. RHA inspection is not currently applicable to this drawing.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.

6. NOTES

6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractorprepared specification or drawing.

6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated as specified in MIL-PRF-38534.

6.4 <u>Record of users</u>. Military and industrial users shall inform DLA Land and Maritime when a system application requires configuration control and the applicable SMD to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-0547.

6.5 <u>Comments</u>. Comments on this drawing should be directed to DLA Land and Maritime-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-1081.

6.6 <u>Sources of supply</u>. Sources of supply are listed in MIL-HDBK-103 and QML-38534. The vendors listed in MIL-HDBK-103 and QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DLA Land and Maritime-VA and have agreed to this drawing.

STANDARD MICROCIRCUIT DRAWING DLA LAND AND MARITIME COLUMBUS, OHIO 43218-3990	SIZE A		5962-98641
		REVISION LEVEL C	SHEET 11

#### STANDARD MICROCIRCUIT DRAWING BULLETIN

### DATE: 12-05-15

Approved sources of supply for SMD 5962-98641 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38534 during the next revisions. MIL-HDBK-103 and QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime -VA. This information bulletin is superseded by the next dated revisions of MIL-HDBK-103 and QML-38534. DLA Land and Maritime maintains an online database of all current sources of supply at http://www.landandmaritime.dla.mil/Programs/Smcr/.

	1	
Standard	Vendor	Vendor
microcircuit drawing	CAGE	similar
PIN <u>1</u> / <u>2</u> /	number	PIN <u>3</u> /
5962-9864101HNA	21845	SDP7915ANHD
5962-9864101HNC	21845	SDP7915ANHG
5962-9864101HTA	21845	SDP7915ATHD
5962-9864101HTC	21845	SDP7915ATHG
5962-9864101HUA	21845	SDP7915AUHD
5962-9864101HUC	21845	SDP7915AUHG
5962-9864101HZA	21845	SDP7915AZHD
5962-9864101HZC	21845	SDP7915AZHG

1/ The lead finish shown for each PIN, representing a hermetic package, is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine availability.

 $\underline{2}/$  The SMD device types listed above are similar to the device types listed on SMD 5962-88748.

3/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number Vendor name and address

21845

Solitron Devices, Incorporated 3301 Electronics Way West Palm Beach, FL 33407

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.